

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/828,149	WASENIUS, REIDAR	
Examiner		Art Unit		Page 1 of 1
Raymond S. Dean		2684		

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B	US-6,901,434	05-2005	Lunsford et al.	709/216
C	US-			
D	US-			
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F	US-			
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H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
U	Haartsen, J.C.; Mattisson, S.; Proceedings of the IEEE, Volume: 88, Issue: 10, Oct. 2000 Pages 1651 - 1661		
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(e).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.